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JUN 14 2004
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Form PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT

DOCKET	S.N.
KPO10801	10/685,847
APPLICANT: Emiko Nishida, et al.	
FILING DATE: October 14, 2003	GROUP: 1762

U.S. PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO
AB	JP	09 0 3 3 2 2 3	2-7-97	JAPAN, with English abstract				X
AB	JP	62 2 2 7 1 0 2	10-6-87	JAPAN, with English abstract				X

OTHER DOCUMENTS (*Including Author, Title, Date, Pertinent Pages, etc.*)

EXAMINER	DATE CONSIDERED
/Alain Bashore/ (12/26/2006)	

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AB			Grèzes-Bessset, et al., "Synthesis and research of the optimum conditions for the optical monitoring of non-quarter-wave multilayers," Applied Optics, Optical Society of America, Wash. US, vol 32, no 28, 10/1/93, pp..5612-5618
AB			S. Callard, et al., "New method for in situ control of Bragg reflector fabrication," Applied Physics Letters, American Institute of Physics, New York, US, vol. 68, no. 17, April 22, 1996, pages 2335-2336
AB			M. Kildemo, et al., "A direct robust feedback method for growth control of optical coatings by multiwavelength ellipsometry," Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH, vol. 313-314, Feb. 13, 1998, pages 484-489

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